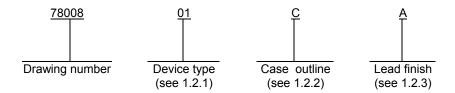
						REVISI	ONS										
LTR			DES	CRIPTIO	N					DATE (YR-MO-DA)		APPROVED					
С	Change to milit	ary drawin Change lir	g format. I	Page 4, ta imes.	ble I, d	elete 50	00 pF to	ests for	rise	86-10-30		M. A. Frye					
D	Add device type 02 to drawing.									87-0	06-22			M. A	. Frye		
E	Add vendor CAGE 04713 for devices 02CX, 02GX, and 02F vendor CAGE 27014 for device 02. Add case outline D-4. table I and figure 1. Make changes to 1.3, 1.4, and editorial throughout. Placed 01CX device back on drawing and char available from an approved source.				D-4. N ditorial	Make cl change	nanges es		89-01-27		M. A. Frye						
F	Add vendor CA CAGE 04713 fr source. Editoria	GE 27014	for device	type 02P	K not a	vailable	from a	n appr	oved		90-1	10-31			M. A. Frye		
G	For device type current requirer			litions of \	o <sub>L</sub> test	. Upda	te draw	ing to			04-0	)4-14		F	Raymon	ıd Monr	nin
Н	Add to figure 1, changes throug	device ty hout dry	oe 01, P pa v	ickage ter	minal c	onnect	ions. E	ditorial	I		05-0	03-08		F	Raymon	ıd Monr	nin
THE ORIGINATE REV SHEET REV SHEET REV STATUS OF SHEETS	AL FIRST SHEE	REV		/ING HA	S BEE	N REF	PLACE H	D.	H 6	H 7	H 8						
PMIC N/A			PARED BY			<u> </u>	-		0				1				
STAI MICRO		Joseph A. Kerby  CHECKED BY  Charles E. Besore				DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990 http://www.dscc.dla.mil											
THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE		DRA	APPROVED BY  Michael A. Frye  DRAWING APPROVAL DATE  78-07-21				MICROCIRCUIT, DIGITAL, MOS CLOCK DRIV MONOLITHIC SILICON				RIVE	RS,					
AM	SC N/A	REV	ISION LEV	ÆL H			,	ZE 4		GE CC				78	800		
						SHEET 1 OF 8											

# 1. SCOPE

- 1.1 <u>Scope</u>. This drawing describes device requirements for MIL-STD-883 compliant, non-JAN class level B microcircuits in accordance with MIL-PRF-38535, appendix A.
  - 1.2 Part or Identifying Number (PIN). The complete PIN is as shown in the following example:



1.2.1 <u>Device types</u>. The device types identify the circuit function as follows:

Device type	Generic number	<u>Circuit function</u>				
01 02	0056 0026	MOS clock driver, with $V_{BB}$ connection $\underline{1}/$				

1.2.2 <u>Case outlines</u>. The case outlines are as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	<u>Terminals</u>	Package style
С	GDIP1-T14 or CDIP2-T14	14	dual-in-line
G	MACY1-X8	8	can
Р	GDIP1-T8 or CDIP2-T8	8	dual-in-line

- 1.2.3 Lead finish. The lead finish is as specified in MIL-PRF-38535, appendix A.
- 1.3 Absolute maximum ratings.

Supply voltage (V+ - V-)	22 V dc
Input voltage (V <sub>IN</sub> - V-)	
Storage temperature	
Maximum power dissipation ( $P_D$ ), $T_A = +25^{\circ}C$ :	
Case C	1380 mW
Case G	
Case P	830 mW
Lead temperature (soldering 10 seconds)	+300°C
Thermal resistance, junction-to-case (θ <sub>JC</sub> ):	
Cases C, G, and P	See MIL-STD-1835
Thermal resistance, junction-to-ambient (θ <sub>JA</sub> )	
Junction temperature (T <sub>J</sub> )	
Peak output current	
Input current	

1.4 Recommended operating conditions.

Supply voltage (V+ - V-)	10 V dc to 20 V dc
Ambient operating temperature range (T <sub>A</sub> )	-55°C to +125°C

Device type 01 is provided with back bias voltage (V<sub>BB</sub>) connection to supply a higher voltage to the output stage. This aids in pulling up the output when it is in the high state. An external resistor tied between these extra pins and a supply higher than V+ will cause the output to pull up to (V+ - 0.1 V) in the off-state.

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# 2. APPLICABLE DOCUMENTS

- 2.1 <u>Government specification, standards, and handbooks</u>. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.
- 2.1 <u>Government specification, standards, and handbooks</u>. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

# DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

# DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.

MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

#### DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.

MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <a href="http://assist.daps.dla.mil;quicksearch/">http://assist.daps.dla.mil;quicksearch/</a> or <a href="http://assist.daps.dla.mil;quicksearch/">www.dodssp.daps.mil</a> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

# 3. REQUIREMENTS

- 3.1 <u>Item requirements</u>. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.
- 3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.
  - 3.2.1 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
  - 3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.
- 3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

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# TABLE I. <u>Electrical performance characteristics</u>.

Test	Symbol	$\begin{tabular}{lll} Conditions & $\underline{1}/$ \\ -55^{\circ}C \le T_{A} \le +125^{\circ}C \\ unless & otherwise & specified \\ \end{tabular}$		Device type	Limits		Unit
					Min	Max	
High level output voltage	V <sub>OH</sub>	$V_{IN}$ - V- = 0.4 V, $R_{BB}$ = 1 k $\Omega$ , $V_{BB} \ge V+$ +1.0 V	1, 2, 3	01	V+ -0.3		V
		V <sub>IN</sub> - V- = 0.4 V, I <sub>L</sub> = -100 μA		02	V+ -1.0		
Low level output voltage	V <sub>OL</sub>	V <sub>IN</sub> - V- = 2.4 V, I <sub>L</sub> = -100 μA	1, 2, 3	All		V- +1.0	V
High level input current	I <sub>IH</sub>	V <sub>IN</sub> - V- = 2.4 V	1, 2, 3	All		15	mA
Low level input current	I <sub>IL</sub>	V <sub>IN</sub> - V- = 0 V	1, 2, 3	All		-15	μΑ
Supply current, "ON"	I <sub>CC(ON)</sub>	V+ - V- = 20 V, V <sub>IN</sub> - V- = 2.4 V	1, 2, 3	01		30	mA
				02		40	
High level input voltage	V <sub>IH</sub>	V <sub>OUT</sub> = V- +1.0 V	1, 2, 3	All	2.0		V
Low level input voltage	V <sub>IL</sub>	V <sub>OUT</sub> = V+ -1.0 V	1, 2, 3	All		0.4	V
Turn on delay	t <sub>PHL</sub>	C <sub>L</sub> = 1,000 pF <u>2</u> /	9, 10, 11	All	5.0	17	ns
Turn off delay	t <sub>PLH</sub>	C <sub>L</sub> = 1,000 pF <u>2</u> /	9, 10, 11	All	5.0	18	ns
Rise time	t <sub>r</sub>	C <sub>L</sub> = 1,000 pF <u>2</u> /, <u>3</u> /	9	All		35	ns
			10, 11			38	
Fall time	t <sub>f</sub>	C <sub>L</sub> = 1,000 pF <u>2</u> /	9	All		30	ns
			10, 11			35	

<sup>1/</sup> These specifications apply for V+ - V- = 10 V to 20 V.

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<sup>2/</sup> Subgroups 10 and 11 if not tested, shall be guaranteed ti the limits specified in table I.

<sup>3/</sup> Rise time is transition from logic "0" to logic "1" which is voltage fall.

Device types	01				02	
Case outlines	С	G	Р	С	G	Р
Terminal number	Terminal symbol					
1	NC	OUTPUT A	V <sub>BB</sub> A	NC	OUTPUT A	NC
2	$V_{BB}A$	$V_{BB}A$	INPUT A	NC	NC	INPUT A
3	OUTPUT A	INPUT A	V-	OUTPUT A	INPUT A	V-
4	NC	V-	INPUT B	NC	V-	INPUT B
5	INPUT A	INPUT B	OUTPUT B	INPUT A	INPUT B	ОИТРИТ В
6	NC	$V_{BB}B$	V <sub>BB</sub> B	NC	NC	V+
7	V-	OUTPUT B	V+	V-	OUTPUT B	OUTPUT A
8	NC	V+	OUTPUT A	NC	V+	NC
9	NC			NC		
10	INPUT B			INPUT B		
11	NC			NC		
12	ОИТРИТ В			OUTPUT B		
13	V <sub>BB</sub> B			NC		
14	V+			V+		

FIGURE 1. Terminal connections.

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- 3.5 <u>Marking</u>. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked.
- 3.5.1 <u>Certification/compliance mark</u>. A compliance indicator "C" shall be marked on all non-JAN devices built in compliance to MIL-PRF-38535, appendix A. The compliance indicator "C" shall be replaced with a "Q" or "QML" certification mark in accordance with MIL-PRF-38535 to identify when the QML flow option is used.
- 3.6 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.
- 3.7 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.
  - 3.8 Notification of change. Notification of change to DSCC-VA shall be required for any change that affects this drawing.
- 3.9 <u>Verification and review</u>. DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

#### 4. VERIFICATION

- 4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test, method 1015 of MIL-STD-883.
    - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
    - (2)  $T_A = +125^{\circ}C$ , minimum.
  - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)
Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004)	1*, 2, 3, 9
Group A test requirements (method 5005)	1, 2, 3, 9, 10**, 11**
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

- \* PDA applies to subgroup 1.
- \*\* Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.
- 4.3 <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
  - 4.3.1 Group A inspection.
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 4, 5, 6, 7, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
      - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
      - (2)  $T_A = +125^{\circ}C$ , minimum.
      - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.
- 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished using DD Form 1692, Engineering Change Proposal.
- 6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Supply Center Columbus (DSCC) when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.
- 6.5 <u>Comments</u>. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-0547.
- 6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

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# STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 05-03-08

Approved sources of supply for SMD 78008 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38535 during the next revision. MIL-HDBK-103 and QML-38535 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This information bulletin is superseded by the next dated revision of MIL-HDBK-103 and QML-38535. DSCC maintains an online database of all current sources of supply at <a href="http://www.dscc.dla.mil/Programs/Smcr/">http://www.dscc.dla.mil/Programs/Smcr/</a>.

Standard microcircuit drawing PIN <u>1</u> /	Vendor CAGE number	Vendor similar PIN <u>2</u> /
7800801CA	3V146	DS0056J/883
7800801GA	3V146	DS0056H/883
7800801PA	3V146	DS0056J-8/883
7800802CA	3V146	DS0026J/883
	<u>3</u> /	0026/BCAJC
7800802GA	3V146	DS0026H/883
	<u>3</u> /	0026/BGAJC
7800802PA	<u>3</u> /	0026/BPAJC

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- <u>2</u>/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ Not available from an approved source of supply.

Vendor CAGEVendor namenumberand address

3V146 Rochester Electronics 10 Malcolm Hoyt Drive

10 Malcolm Hoyt Drive Newburyport, MA 01950

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.